

Session Title: 53, Oxide TFTs 1

Session Date: August 22 (Fri.), 2025

Session Time: 11:00-12:30

Session Room: Room E (311~312)

Session Chair(s): Prof. Youngki Yoon (Univ. of Waterloo, Canada)

Prof. Jung-Hwan Kim (UNIST, Korea)

[E53-1] [Invited] 11:00-11:25

The Impact of Defects on the Stability of Oxide Semiconductor Devices

Mengwei Si (Shanghai Jiao Tong Univ., China)

[E53-2] [Invited] 11:25-11:50

The Reliability, Mobility, and 3D Integration of BEOL IGZO Transistors

Tang Baoshan, Sonu Hooda, and Aaron Voon-Yew Thean (Nat'l Univ. of Singapore, Singapore)

[E53-3] [Invited] 11:50-12:15

Asymmetric Double-Gate (ADG) Oxide TFTs for Display and Sensor

Yuhan Zhang, Tengyan Huang, Huan Yang, Congwei Liao, and Shengdong Zhang (Peking Univ., China)

[E53-4] 12:15-12:30

On Enhancing the Thermal Stability of a Metal-Oxide Thin-Film Transistor

Wei Jiang, Qiuxiao Feng (HKUST, China), and Man Wong (The Hong Kong Univ. of Science and Tech. & The Hong Kong Univ. of Science and Tech. Shenzhen Inst., China)